

## Instant Analysis



### DEKTAK II A

The Bruker Dektak II A is a tactile profilometer for measuring surface roughness or film thickness on prepared samples.

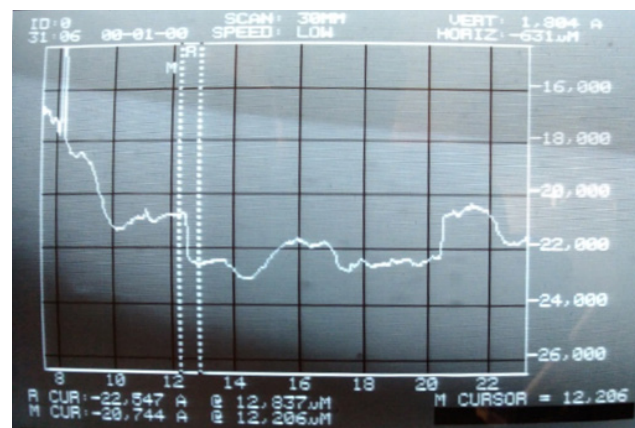
Tactile profilometers measure the force against a small needle and that is moved lateral to the sample. This force is kept constant by changing the position of that needle via a small piezo in Z direction. The piezo movement is logged and gives a height profile of the sample.

#### Technical Data

<b>Measurement Range</b>	0 - 50 $\mu\text{m}$
<b>Profile length</b>	30 mm
<b>Limitations Film Thickness Measurement</b>	Sample needs a Step for every layer thickness that needs measuring
<b>Sample Size</b>	Dia. 150 x 10 mm



Step of 180 nm Aluminum on float glass – Zoom on Step



Step of 180 nm Aluminum on float glass – Full Scan